

**● PRINTER RUSH ●**  
**(PTO ASSISTANCE)**

Application :	10/693,201	Examiner :	T. HOLLINGTON
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		Tracking #:	<u>6121463</u>
		Week Date:	<u>7/4/05</u>

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<input type="checkbox"/> DRW		
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<input type="checkbox"/> SPEC		

[RUSH] MESSAGE: CLAIMS 1 + 4 ARE ILLEGIBLE. PLEASE  
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[XRUSH] RESPONSE:
8-24-05 completed
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INITIALS: <u>rb</u>

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 REV 10/04

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Complete Listing of Claims:**

1. (Currently amended) A method of fabricating a plurality of micro probes comprising the steps of:

providing one or more masks, each of said one or more masks including defining the shapes of a plurality of probe(s) shapes as a mask, each of said plurality of probe shapes including a probe base, a probe shaft connected to said probe base, a probe end connected to said probe shaft, and one or more raised surfaces on at least one of said probe base, said probe end and said probe shaft;

applying a photoresist to a side of a first metal material;  
overlaying said mask on said side of said first metal material;  
exposing said photoresist to light passed through said mask;  
developing said photoresist;  
removing a portion of said photoresist to expose a portion of said first metal material;  
electroforming a second metal material on said exposed portions of said first metal material; and

removing said second metal material to produce a plurality of probes, each of said plurality of probes including a probe base, a probe shaft connected to said probe base, a probe end connected to said probe shaft, and one or more raised surfaces on at least one of said probe base, said probe end, and said probe shaft.

2. (Original) The method of claim 1 wherein said first material is stainless steel.

3. (Original) The method of claim 1 wherein said second material is selected from one of Nickel and Nickel-Cobalt alloy.

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probe  
probe

4. (Currently amended) A micro probe manufactured according to the method of claims said-micro-probe comprising:

a probe base having a generally uniform thickness bounded by a plurality of edges and extending for a substantially straight length in a plane;

Connected a probe shaft connected to said probe base said probe shaft of said generally uniform thickness, bounded by a plurality of edges, and extending along a curved expanse within said plane;

Connected a probe end connected to said probe shaft said probe end of said generally uniform thickness, bounded by a plurality of edges, and extending for a substantially straight distance within said plane said straight distance being approximately parallel to said straight length; and

one or more raised surfaces positioned on at least one of said probe base, said probe shaft, and said probe end, wherein said one or more raised surfaces are formed from a mechanical process a scallop running substantially around a periphery comprised of the edges of said probe base, said probe shaft, and said probe end.

5. (Original) The micro probe of claim 4 wherein said uniform thickness is between 2 mils and 5 mils.

6. (Original) The micro probe of claim 5 wherein said uniform thickness is between 3 mils and 4 mils.

7. (Original) The micro probe of claim 6 wherein said scallop further comprises a scallop base and a scallop tip.

8. (Original) The micro probe of claim 7 wherein said scallop base and said scallop tip are separated by a substantially uniform distance.

Claims 9-22 (Cancelled)

23. (New) The micro probe of claim 4 wherein said mechanical process is an electroforming process.